

**Search Notes**

Application/Control No.

10/045,348

Examiner

Mark A. Mais

Applicant(s)/Patent under  
Reexamination

SHIN ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner
370	389 392 394	9/15/2006	MAM
	395.4 400		
	412-418		
	428 429		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See Attached Electronic Search	9/15/2006	MAM